

10/520 433

DT15
PCT/PTO 06 JAN 2005
PATENT
450100-04676

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Takuji HIMENO et al.
International Application No.: PCT/JP03/08431
International Filing Date: July 2, 2003
For: IMAGE DATA PROCESSING APPARATUS AND METHOD

745 Fifth Avenue
New York, NY 10151

EXPRESS MAIL

Mailing Label Number: EV206809627US
Date of Deposit: January 6, 2005

I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" Service under 37 CFR 1.10 on the date indicated above and is addressed to Mail Stop PCT, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Charles Jackson
(Typed or printed name of person mailing paper or fee)
Charles Jackson
(Signature of person mailing paper or fee)

INFORMATION DISCLOSURE STATEMENT

Mail Stop PCT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Enclosed are copies of the publications, which were cited in the International Search Report of International Application No. PCT/JP03/08431. Also enclosed is a copy of Form PTO-1449 and the International Search Report.

10/520 433
DT15 Rec'd PCT/PTO 06 JAN 2005
PATENT
450100-04676

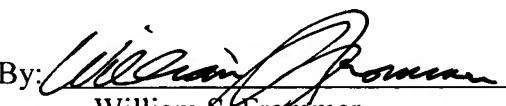
REMARKS

Entry of this Information Disclosure Statement and an early examination on the merits are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP
Attorneys for Applicants

By: 
William S. Frommer
Reg. No. 25,506
Tel. (212) 588-0800

Enclosures

071520459
06 JAN 2005

Sheet 1 of 1

Based on Form PTO-1449 (3/90)		ATTY. DOCKET NO. 450100-04676	SERIAL NO. 0071520459 Filed Concurrently Herewith
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Takuji HIMENO et al.	
		FILING DATE Filed Concurrently Herewith	GROUP

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AL	JP 11-205734	07/30/99	Japan			
	AM	JP 2000-92448	03/31/00	Japan			
	AN	JP 2001-275077	10/05/01	Japan			
	AO						
	AP						

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ		
	AR		
	AS		

EXAMINER	DATE CONSIDERED		

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.